

Notice of References Cited

Application/Control No.

10/573,627

Applicant(s)/Patent Under
Reexamination
ROEHM ET AL.

Examiner

M'baye Diao

Art Unit

2838

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0070511	04-2003	Nottingham et al.	81/54
*	B	US-4,751,452	06-1988	Kilmer et al.	320/106
*	C	US-6,364,033	04-2002	Hung et al.	173/217
*	D	US-4,078,589	03-1978	Miller, Walter L.	81/57.14
*	E	US-6,510,768	01-2003	Fruhm, Hermann	81/490
*	F	US-4,493,223	01-1985	Kishi et al.	74/371
*	G	US-2006/0104735	05-2006	Zeiler et al.	408/241.00R
*	H	US-3,329,185	07-1967	ALFRED HETTICH; et. al.	81/58.1
*	I	US-4,804,048	02-1989	Porth, Jr., Chris H.	173/47
*	J	US-6,102,134	08-2000	Alsrue, Wallis	173/217
*	K	US-5,496,139	03-1996	Ghode et al.	409/182
*	L	US-4,951,756	08-1990	Everett et al.	173/178
*	M	US-3,369,615	02-1968	MAFFEY JR GEORGE E; et. al.	173/93.6

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
<input checked="" type="checkbox"/>	N	GB 2375497 A	11-2002	United Kingdom	LIU, KUO-CHEN	
	O					
	P					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0130007	09-2002	Nakamura et al.	192/38
*	B	US-2003/0015066	01-2003	Chao, Shenq Ruey	81/57.26
*	C	US-4,677,362	06-1987	House et al.	320/115
*	D	US-2002/0184979	12-2002	Fruhm, Hermann	81/490
*	E	US-5,054,563	10-1991	Zapf, Jurgén	173/217
*	F	US-5,336,953	08-1994	Allemann, Markus	310/50
*	G	US-6,702,530	03-2004	Bennage et al.	408/241R
*	H	US-6,151,741	11-2000	Chen, Martin	7/155
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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